RAEF: A Power Normalized Systemlevel Reliability Analysis and Estimation Framework

R.A. Shafik¹, Bashir M. Al-Hashimi², J. Mathew¹, D.K. Pradhan¹ and S.P. Mohanty³

¹Dept of Computer Science, University of Bristol, UK ²School of Electronics and Computer Science, University of Southampton, UK ³Dept of Computer Science and Engineering, University of North Texas, USA

> Presenter: Geng Zheng University of North Texas Email: gengzheng@my.unt.edu









1

Outline

- Introduction: System-level Reliable Design
- Motivations and Contributions
- Power Normalized Reliability Metric
- RAEF: Proposed Reliability Estimation Framework
- Results: MPEG-2 Decoder and Other Applications
- Conclusions







Introduction

• Reliability in the presence of soft errors is an emerging design challenge

– Further exacerbated by continued technology scaling

- System-level design is highly effective in reliable multiprocessor system-on-chip (MPSoC) design
- A crucial aspect in such design is to estimate the reliability in early design phase
 - with an aim to assess the comparative component reliabilities and design low-cost reliable system







Previous Work

- To estimate reliability at system-level various approaches have been used over the years
 - Hierarchical Monte-Carlo based estimation from component-level to MPSoC system [Xiang *et al*]
 - MTTF based MPSoC reliability model based on statistical modelling [Coskun *et al*]
 - Mean Error Impact based MPSoC reliability model [Wu and Marculescu]
 - Reliability metric based system-level analysis and estimation [Zhao *et al*]







Motivation

- Currently power and reliability estimations are carried out separately
- Since power minimization directly affects reliability, component reliability comparisons do not signify joint consideration of power and reliability
 - Which is much needed for a system where low power and high reliability are joint objectives
- Hence, a composite metric is much needed highlighting power and reliability trade-offs







Motivation

[Examples of separate measurements]

Component	Scaling	Reliability	Power, mW
comp1	66.7MHz @ 0.55V	0.96	0.98
comp2	100MHz @ 0.6V	0.98	1.96
comp3	200MHz @ 1V	0.99	9.24

- *comp1* has low power but low reliability; achieved through aggressive voltage scaling
- *comp3* has high reliability at the expense of high power; no voltage scaling applied
- *comp2* has reliability of 0.98 and a power consumption of 1.98mW
- With separate power and reliability measurements, it is hard to comparatively assess the system reliability







Contribution

- We propose a novel composite metric, called power normalized reliability (PNR)
 - Expressed as a ratio of system reliability and power
 - Aim is to highlight power and reliability trade-offs at system- and component-level
- Underpinning this metric, a novel estimation framework, reliability analysis and estimation framework (RAEF) is presented
 - For effective fault injection, analysis and estimation at various architectural hierarchies: register-level, corelevel and system-level







Power Normalized Reliability (PNR)

$$PNR = \frac{R}{P} = \frac{exp\left[-\hat{\lambda}_0 \ k \ v \ t\right]}{\alpha \ C_L \ V_{dd}^2 f}$$

R is reliability expressed as a function of basic soft error rate (λ_o) , factor of soft error increase with voltage scaling (k), architectural vulnerability factor (v) and time (t)

P is dynamic power expressed as a function of activity factor (α), load capacitance (C_L), supply voltage (V_{dd}) and operating frequency (*f*)







Power versus PNR



- PNR is high at lower power and low at higher power
- It varies significantly due to different activity factors







RAEF: Proposed Estimation Framework



Southampton





Fault Injection in RAEF



- Fault injection enabler types form a fault locations database
- Faults are injected at random times/locations based on fault policy







Hierarchical PNR Estimation [@ Register-level]

• PNR is estimated for each register in design specification

 $PNR_{i,c} = \frac{R_{i,c}}{P_{i,c}} = \frac{\exp\left[-g_{i,c}k_c\lambda_b t\right]}{\frac{t_{i,c}^b}{t}C_L V_{dd}^2 f}$ is reliability (error rate (λ_b , per bit per unit time), factor of soft error increase with voltage scaling on *c*-th core (k_c), size of the register ($g_{i,c}$) and time (t)

 $P_{i,c}$ is dynamic power of *i*-th register in *c*-th core expressed as a function of register activity factor ($\alpha_{i,c}$: ratio of busy cycles, $t^{b}_{i,c}$ and time, *t*), load capacitance (C_L), supply voltage (V_{dd}) and operating frequency (*f*)

NOTE: at this level vulnerability does not affect component reliability







Hierarchical PNR Estimation [@ Processing Core-level]

• At processing core-level PNR is estimated for each core as

$$PNR_{c} = \frac{R_{c}}{P_{c}} = \frac{\exp\left[-\sum_{i=1}^{G_{c}} \lambda_{i,c} \left(\Gamma_{i,c}^{V}/\Gamma_{i,c}^{A}\right)t\right]}{\frac{t_{c}^{b}}{t} C_{L} V_{dd}^{2} f}$$

 R_c is reliability of *c*-th core expressed as a function of component soft error rate ($\lambda_{i,c}$, per bit per unit time), component vulnerability factor (*v*: ratio of visible fault, $\Gamma_{i,c}^V$ and actual number of fault injected, $\Gamma_{i,c}^A$), and time (*t*)

 P_c is dynamic power of *c*-th core expressed as a function of core activity factor ($\alpha_{i,c}$: ratio of busy cycles, t^b_c and time, *t*), load capacitance (C_L), supply voltage (V_{dd}) and operating frequency (*f*) **NOTE**: At higher architectural level, vulnerability becomes important.







Hierarchical PNR Estimation [@ System-level]

• At system-level, PNR is estimated for the overall MPSoC system as

$$PNR = \exp\left[-\sum_{c=1}^{C} \lambda_c \left(\Gamma_c^V / \Gamma_c^A\right) t\right] / \sum_{c=1}^{C} P_c$$

Reliability of MPSoC system is expressed as a function of per core core soft error rate (λ_c , per bit per unit time), component vulnerability factor (*v*: ratio of visible fault per core, Γ_c^V and actual number of fault injected per core, Γ_c^A), and time (*t*)

Overall power *is* expressed as a sum of core dynamic powers

NOTE: At system-level, PNR is determined by various factors including component vulnerability, activity factor and observation time.







Case Study: MPEG-2 Decoer

- MPSoC with four decoder cores
- RAEF will be used to examine PNR based reliability at
 - register-level
 - core-level and
 - overall system-level.









PNR Estimates at Register-level



- Longer registers have low reliability and hence lower PNR
- Registers with low activity factor have high PNR
- **COMMENT**: PNR clearly signifies the trade-off, while traditional reliability fails to do so







PNR Estimates at Core-level



- Processing cores with low activity & vulnerability factor have high PNR
- **COMMENT**: At core level, reliability metric has minor variations and does not highlight power trade-off; PNR overcomes this.







Impact of Voltage Scaling [and activity factor]



Processing cores with low activity factor has low power and hence higher PNR; Voltage scaling significantly improves PNR

NOTICE: Core VLD (which has lowest overall activity factor) has the highest PNR, while core MC (which has the highest overall activity factor) has the lowest PNR







PNR Estimates at System-level [Impact of Architecture Allocations]



With higher architecture allocation, register usage increases, which also degrades core reliabilities and hence overall PNR







PNR Estimates at System-level [Difference between various applications]



Applications with higher activity factor and higher register usage had lower overall PNR; hence, MPEG-2 is outperformed by other applications shown

Southampton





Conclusions

- Proposed PNR based estimation is highly effective
 - It highlights the comparative reliability between components, taking into consideration power and reliability jointly
- Using PNR, an analysis and estimation framework (RAEF) was shown
 - Enables PNR based insightful analysis and estimation using system-level simulation techniques
- The effectiveness of RAEF using PNR was evaluated
 - Using MPEG-2 and various other applications
 - Considering the impact of voltage scaling, architecture allocation and observation times on PNR







THANK YOU





